2SD1350, 2SD1350A

Silicon NPN triple diffusion planar type

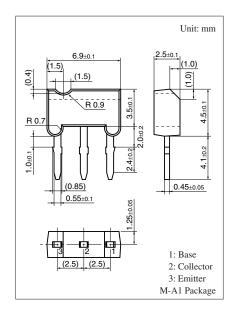
For high breakdown voltage switching

Features

- \bullet High collector-base voltage (Emitter open) V_{CBO}
- \bullet Large collector power dissipation P_{C}
- \bullet Low collector-emitter saturation voltage $V_{\mbox{CE(sat)}}$
- M type package, allowing easy automatic and manual insertion as well as stand-alone fixing to the printed circuit board.

Parameter	Cumbal	Dating	Unit		
Falaillelei	Symbol	Rating	Unit		
Collector-base voltage	2SD1350	V _{CBO}	400	V	
(Emitter open)	2SD1350A		600		
Collector-emitter voltage	2SD1350	V _{CEO}	400	V	
(Base open)	2SD1350A		500		
Emitter-base voltage (Coll	V _{EBO}	5	V		
Collector current	I _C	500	mA		
Peak collector current	I _{CP}	1	А		
Collector power dissipatio	P _C	1	W		
Junction temperature	Tj	150	°C		
Storage temperature	T _{stg}	-55 to +150	°C		





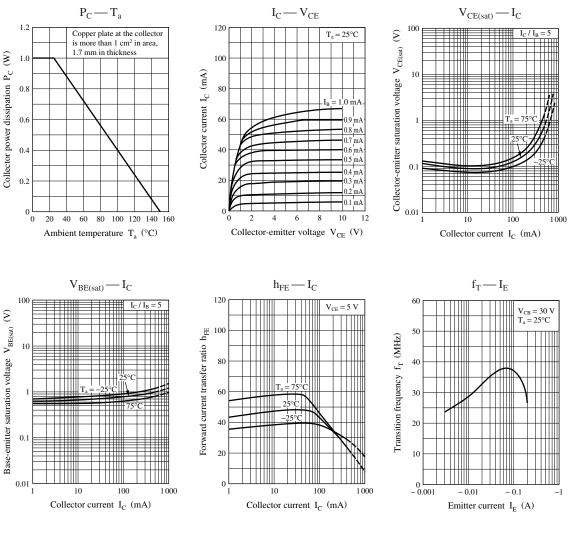
Note) *: Printed circuit board: Copper foil area of 1 cm² or more, and the board thickness of 1.7 mm for the collector portion

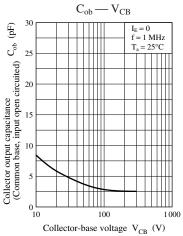
Electrical Characteristics $T_a = 25^{\circ}C \pm 3^{\circ}C$

Parameter		Symbol	Conditions	Min	Тур	Max	Unit
Collector-base voltage	2SD1350	V _{CBO}	$I_{C} = 100 \ \mu A, I_{E} = 0$	400			V
(Emitter open)	2SD1350A			600			
Collector-emitter voltage	2SD1350	V _{CEO}	$I_{C} = 500 \ \mu A, I_{B} = 0$	400			V
(Base open)	2SD1350A			500			
Emitter-base voltage (Collector open)		V _{EBO}	$I_E = 100 \ \mu A, \ I_C = 0$	5			V
Forward current transfer ratio		h _{FE}	$V_{CE} = 5 \text{ V}, I_C = 30 \text{ mA}$	30			
Collector-emitter saturation voltage		V _{CE(sat)}	$I_{\rm C} = 250 \text{ mA}, I_{\rm B} = 50 \text{ mA}$			1.5	V
Base-emitter saturation voltage		V _{BE(sat)}	$I_{\rm C} = 250 \text{ mA}, I_{\rm B} = 50 \text{ mA}$			1.5	V
Transition frequency		f _T	$V_{CB} = 30 \text{ V}, I_E = -20 \text{ mA}, f = 200 \text{ MHz}$		55		MHz
Collector output capacitance		C _{ob}	$V_{CB} = 30 \text{ V}, I_E = 0, f = 1 \text{ MHz}$			7	pF
(Common base, input open circuited)							
Turn-on time		t _{on}	$V_{CC} = 200 \text{ V}, I_C = 100 \text{ mA}$		0.4		μs
			$I_{B1} = 10 \text{ mA}, I_{B2} = -10 \text{ mA}$				
Fall time		t _f	$V_{CC} = 200 \text{ V}, I_C = 100 \text{ mA}$		0.7		μs
			$I_{B1} = 10 \text{ mA}, I_{B2} = -10 \text{ mA}$				
Storage time		t _{stg}	$V_{CC} = 200 \text{ V}, I_C = 100 \text{ mA}$		3.6		μs
			$I_{B1} = 10 \text{ mA}, I_{B2} = -10 \text{ mA}$				

Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

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